

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74VCXR162600FT

LOW-VOLTAGE 18-BIT UNIVERSAL BUS TRANSCEIVER WITH 3.6 V TOLERANT INPUTS AND OUTPUTS

The TC74VCXR162600FT is a high performance CMOS 18-bit UNIVERSAL BUS TRANSCEIVER. Designed for use in 1.8, 2.5 or 3.3 Volt systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

It is also designed with over voltage tolerant inputs and outputs up to 3.6 V.

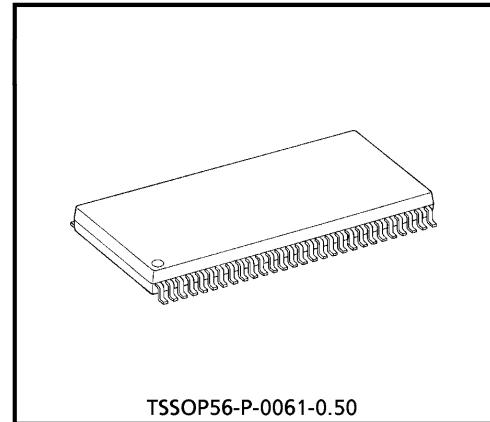
Data flow in each direction is controlled by output-enable (\overline{OEAB} and \overline{OEBA}), latch-enable (LEAB and LEBA), and clock (\overline{CKAB} and \overline{CKBA}) inputs. The clock can be controlled by the clock-enable (\overline{CKENAB} and \overline{CKENBA}) inputs. For A-to-B data flow, the device operates in the transparent mode when LEAB is high. When LEAB is low, the A data is latched if \overline{CKAB} is held at a high or low logic level. If LEAB is low, the A-bus data is stored in the latch/flip-flop on the high-to-low transition of \overline{CKAB} .

Data flow for B to A is similar to that of A to B but uses \overline{OEBA} , LEBA, \overline{CKBA} , and \overline{CKENBA} . When the \overline{OE} input is high, the outputs are in a high impedance state. This device is designed to be used with 3-state memory address drivers, etc.

The $26\text{-}\Omega$ series resistor helps reducing output overshoot and undershoot without external resistor. All inputs are equipped with protection circuits against static discharge.

FEATURES

- 26- Ω Series Resistors on Outputs.
- Low Voltage Operation : $V_{CC} = 1.8\sim 3.6V$
- High Speed Operation : $t_{pd} = 3.8\text{ ns (max) at } V_{CC} = 3.0\sim 3.6V$
 : $t_{pd} = 5.1\text{ ns (max) at } V_{CC} = 2.3\sim 2.7V$
 : $t_{pd} = 9.8\text{ ns (max) at } V_{CC} = 1.8V$
- 3.6 V Tolerant inputs and outputs.
- Output Current : $I_{OH}/I_{OL} = \pm 12\text{ mA (min) at } V_{CC} = 3.0V$
 : $I_{OH}/I_{OL} = \pm 8\text{ mA (min) at } V_{CC} = 2.3V$
 : $I_{OH}/I_{OL} = \pm 4\text{ mA (min) at } V_{CC} = 1.8V$
- Latch-up Performance : $\pm 300\text{ mA}$
- ESD Performance : Human Body Model $> \pm 2000\text{ V}$
 : Machine Model $> \pm 200\text{ V}$
- Package : TSSOP (Thin Shrink Small Outline Package)
- Bidirectional interface between 2.5 V and 3.3 V signals.
- Power Down Protection is provided on all inputs and outputs.
- Supports live insertion / withdrawal (Note 3)



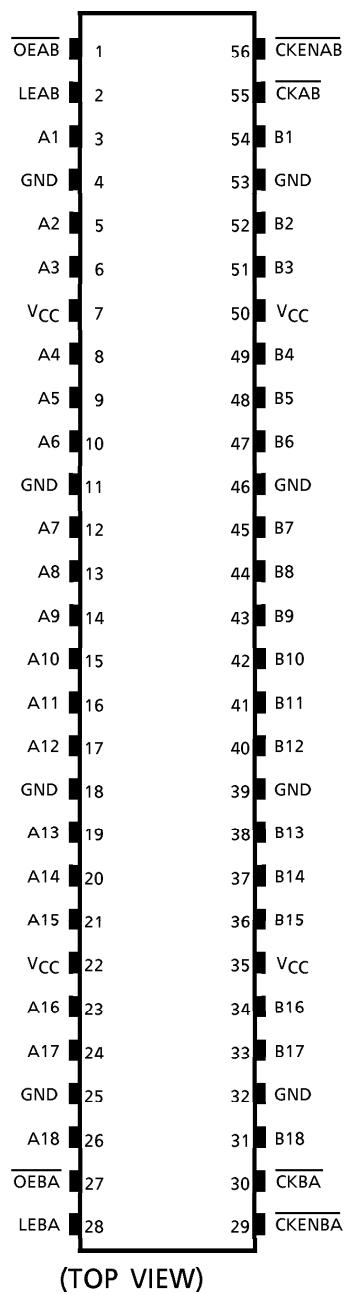
Weight : 0.25 g (Typ.)

(Note 1) : Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.

(Note 2) : All floating (high impedance) bus terminal must have their input level fixed by means of pull up or pull down resistors.

(Note 3) : To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

PIN ASSIGNMENT



(TOP VIEW)

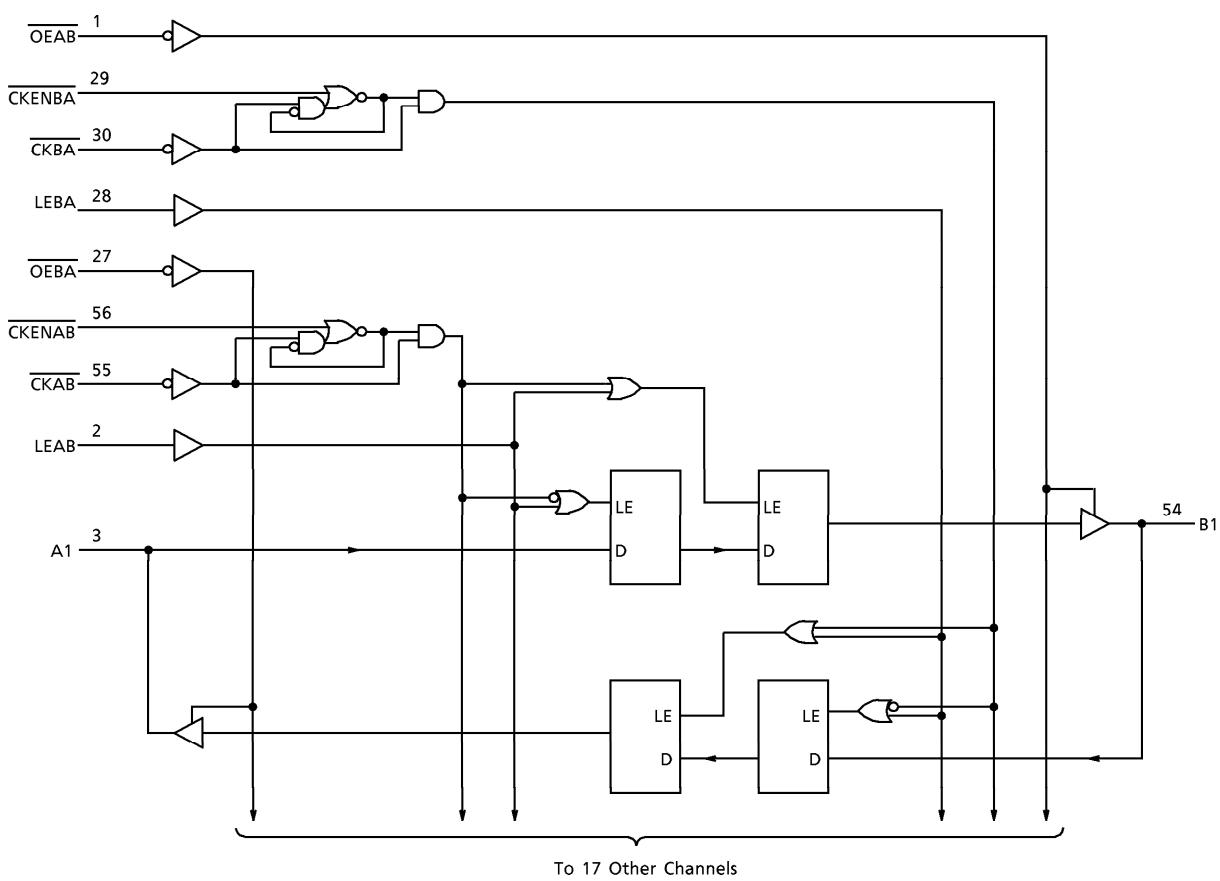
TRUTH TABLE *

INPUTS					OUTPUTS B
\overline{CKENAB}	\overline{OEAB}	LEAB	\overline{CKAB}	A	
X	H	X	X	X	Z
X	L	H	X	L	L
X	L	H	X	H	H
H	L	L	X	X	B_0^{**}
H	L	L	X	X	B_0^{**}
L	L	L	↓	L	L
L	L	L	↓	H	H
L	L	L	H	X	B_0^*
L	L	L	L	X	B_0^*

* A-to-B data flow is shown: B-to-A flow is similar but uses \overline{OEBA} , $LEBA$, \overline{CKBA} , and \overline{CKNB}_A .

** Output level before the indicated steady-state input conditions were established, provided that \overline{CKAB} was low or high before $LEAB$ went low.

SYSTEM DIAGRAM



MAXIMUM RATINGS

PARAMETER	SYMBOL	RATING	UNIT
Power Supply Voltage	V_{CC}	-0.5~4.6	V
DC Input Voltage (OEAB, OEBA, LEAB, LEBA, CKAB, CKBA, CKENAB, CKENBA)	V_{IN}	-0.5~4.6	V
DC Bus I/O Voltage	$V_{I/O}$	-0.5~4.6 (Note 1)	V
		-0.5~ V_{CC} + 0.5 (Note 2)	
Input Diode Current	I_{IK}	-50	mA
Output Diode Current	I_{OK}	± 50 (Note 3)	mA
DC Output Current	I_{OUT}	± 50	mA
Power Dissipation	P_D	400	mW
DC V_{CC} / Ground Current Per Supply Pin	I_{CC}/I_{GND}	± 100	mA
Storage Temperature	T_{stg}	-65~150	°C

(Note 1) : Off-State

(Note 2) : High or Low State. I_{OUT} absolute maximum rating must be observed.(Note 3) : $V_{OUT} < GND$, $V_{OUT} > V_{CC}$ **RECOMMENDED OPERATING RANGE**

PARAMETER	SYMBOL	RATING	UNIT
Supply Voltage	V_{CC}	1.8~3.6	V
		1.2~3.6 (Note 4)	
Input Voltage (OEAB, OEBA, LEAB, LEBA, CKAB, CKBA, CKENAB, CKENBA)	V_{IN}	-0.3~3.6	V
Bus I/O Voltage	$V_{I/O}$	0~3.6 (Note 5)	V
		0~ V_{CC} (Note 6)	
Output Current	I_{OH}/I_{OL}	± 12 (Note 7)	mA
		± 8 (Note 8)	
		± 4 (Note 9)	
Operating Temperature	T_{opr}	-40~85	°C
Input Rise And Fall Time	dt/dv	0~10 (Note 10)	ns/V

(Note 4) : Data Retention Only

(Note 5) : Off-State

(Note 6) : High or Low State

(Note 7) : $V_{CC} = 3.0\sim 3.6$ V(Note 8) : $V_{CC} = 2.3\sim 2.7$ V(Note 9) : $V_{CC} = 1.8$ V(Note 10) : $V_{IN} = 0.8\sim 2.0$ V, $V_{CC} = 3.0$ V

ELECTRICAL CHARACTERISTICSDC characteristics ($T_a = -40\sim85^\circ C$, $2.7 V < V_{CC} \leq 3.6 V$)

PARAMETER		SYMBOL	TEST CONDITION		V_{CC} (V)	MIN	MAX	UNIT	
Input Voltage	"H" Level	V_{IH}			2.7~3.6	2.0	—	V	
	"L" Level	V_{IL}			2.7~3.6	—	0.8		
Output Voltage	"H" Level	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -100 \mu A$	2.7~3.6	$V_{CC} - 0.2$	—	V	
				$I_{OH} = -6 mA$	2.7	2.2	—		
				$I_{OH} = -8 mA$	3.0	2.4	—		
				$I_{OH} = -12 mA$	3.0	2.2	—		
	"L" Level	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 100 \mu A$	2.7~3.6	—	0.2		
				$I_{OL} = 6 mA$	2.7	—	0.4		
				$I_{OL} = 8 mA$	3.0	—	0.55		
				$I_{OL} = 12 mA$	3.0	—	0.8		
Input Leakage Current	I_{IN}	$V_{IN} = 0\sim3.6 V$		2.7~3.6	—	± 5.0	μA		
3-State Output Off-State Current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL}		2.7~3.6	—	± 10.0	μA		
Power Off Leakage Current	I_{OFF}	$V_{IN}, V_{OUT} = 0\sim3.6 V$		0	—	10.0	μA		
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND		2.7~3.6	—	20.0	μA		
		$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 V$		2.7~3.6	—	± 20.0			
Increase In I_{CC} Per Input	ΔI_{CC}	$V_{IH} = V_{CC} - 0.6 V$		2.7~3.6	—	750	μA		

ELECTRICAL CHARACTERISTICSDC characteristics ($T_a = -40\sim85^\circ C$, $2.3 V \leq V_{CC} \leq 2.7 V$)

PARAMETER		SYMBOL	TEST CONDITION		V_{CC} (V)	MIN	MAX	UNIT	
Input Voltage	"H" Level	V_{IH}			2.3~2.7	1.6	—	V	
	"L" Level	V_{IL}			2.3~2.7	—	0.7		
Output Voltage	"H" Level	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -100 \mu A$	2.3~2.7	$V_{CC} - 0.2$	—	V	
				$I_{OH} = -4 mA$	2.3	2.0	—		
				$I_{OH} = -6 mA$	2.3	1.8	—		
				$I_{OH} = -8 mA$	2.3	1.7	—		
	"L" Level	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 100 \mu A$	2.3~2.7	—	0.2		
				$I_{OL} = 6 mA$	2.3	—	0.4		
				$I_{OL} = 8 mA$	2.3	—	0.6		
				$I_{OL} = 12 mA$	2.3~2.7	—	0.8		
Input Leakage Current	I_{IN}	$V_{IN} = 0\sim3.6 V$		2.3~2.7	—	± 5.0	μA		
3-State Output Off-State Current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL}		2.3~2.7	—	± 10.0	μA		
Power Off Leakage Current	I_{OFF}	$V_{IN}, V_{OUT} = 0\sim3.6 V$		0	—	10.0	μA		
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND		2.3~2.7	—	20.0	μA		
		$V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 V$		2.3~2.7	—	± 20.0			

ELECTRICAL CHARACTERISTICSDC characteristics ($T_a = -40\sim85^\circ C$, $1.8 V \leq V_{CC} < 2.3 V$)

PARAMETER		SYMBOL	TEST CONDITION		V_{CC} (V)	MIN	MAX	UNIT
Input Voltage	"H" Level	V_{IH}			1.8~2.3	$0.7 \times V_{CC}$	—	V
	"L" Level	V_{IL}			1.8~2.3	—	$0.2 \times V_{CC}$	
Output Voltage	"H" Level	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -100 \mu A$	1.8	$V_{CC} - 0.2$	—	V
	"L" Level	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 100 \mu A$	1.8	—	0.2	
Input Leakage Current		I_{IN}	$V_{IN} = 0\sim3.6 V$		1.8	—	± 5.0	μA
3-State Output Off-State Current		I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = 0\sim3.6 V$		1.8	—	± 10.0	μA
Power Off Leakage Current		I_{OFF}	$V_{IN}, V_{OUT} = 0\sim3.6 V$		0	—	10.0	μA
Quiescent Supply Current		I_{CC}	$V_{IN} = V_{CC}$ or GND $V_{CC} \leq (V_{IN}, V_{OUT}) \leq 3.6 V$		1.8	—	20.0	μA
					1.8	—	± 20.0	

AC characteristics ($T_a = -40\sim85^\circ C$, Input $t_r = t_f = 2.0 \text{ ns}$, $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$)

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC} (\text{V})$	MIN	MAX	UNIT
			1.8			
Maximum Clock Frequency	f_{MAX}	(Fig.1, 3)	2.5 ± 0.2	200	—	MHz
			3.3 ± 0.3	250	—	
			1.8	1.5	9.8	
Propagation Delay Time (A_n, B_n-B_n, A_n)	t_{pLH} t_{pHL}	(Fig.1, 2)	2.5 ± 0.2	0.8	5.1	ns
			3.3 ± 0.3	0.6	3.8	
			1.8	1.5	9.8	
Propagation Delay Time ($\overline{CKAB}, \overline{CKBA}-B_n, A_n$)	t_{pLH} t_{pHL}	(Fig.1, 3)	2.5 ± 0.2	0.8	6.4	ns
			3.3 ± 0.3	0.6	4.4	
			1.8	1.5	9.8	
Propagation Delay Time ($LEAB, LEBA-B_n, A_n$)	t_{pLH} t_{pHL}	(Fig.1, 4)	2.5 ± 0.2	0.8	5.8	ns
			3.3 ± 0.3	0.6	4.4	
			1.8	1.5	9.8	
Output Enable Time ($\overline{OEAB}, \overline{OEBA}-B_n, A_n$)	t_{pZL} t_{pZH}	(Fig.1, 6)	2.5 ± 0.2	0.8	5.9	ns
			3.3 ± 0.3	0.6	4.3	
			1.8	1.5	8.8	
Output Disable Time ($\overline{OEAB}, \overline{OEBA}-B_n, A_n$)	t_{pLZ} t_{pHZ}	(Fig.1, 6)	2.5 ± 0.2	0.8	4.9	ns
			3.3 ± 0.3	0.6	4.3	
			1.8	4.0	—	
Minimum Pulse Width	$t_w (H)$ $t_w (L)$	(Fig.1, 3, 4)	2.5 ± 0.2	1.5	—	ns
			3.3 ± 0.3	1.5	—	
			1.8	2.5	—	
Minimum Set-up Time	t_s	(Fig.1, 3, 4, 5)	2.5 ± 0.2	1.5	—	ns
			3.3 ± 0.3	1.5	—	
			1.8	2.0	—	
Minimum Hold Time	t_h	(Fig.1, 3, 4, 5)	2.5 ± 0.2	1.5	—	ns
			3.3 ± 0.3	1.0	—	
			1.8	—	0.5	
Output to Output Skew	t_{osLH} t_{osHL}	(Note 11)	2.5 ± 0.2	—	0.5	ns
			3.3 ± 0.3	—	0.5	

For $C_L = 50 \text{ pF}$, add approximately 300 ps to the AC maximum specification.

(Note 11) : Parameter guaranteed by design.

$$(t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|)$$

Dynamic switching characteristics ($T_a = 25^\circ\text{C}$, Input $t_r = t_f = 2.0 \text{ ns}$, $C_L = 30 \text{ pF}$)

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC} (\text{V})$	TYP.	UNIT
Quiet Output Maximum Dynamic V_{OL}	V_{OLP}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	1.8	0.15	V
		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	2.5	0.25	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	3.3	0.35	
Quiet Output Minimum Dynamic V_{OL}	V_{OLV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	1.8	-0.15	V
		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	2.5	-0.25	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	3.3	-0.35	
Quiet Output Minimum Dynamic V_{OH}	V_{OHV}	$V_{IH} = 1.8 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	1.8	1.55	V
		$V_{IH} = 2.5 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	2.5	2.05	
		$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$ (Note 12)	3.3	2.65	

(Note 12) : Parameter guaranteed by design.

Capacitive characteristics ($T_a = 25^\circ\text{C}$)

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC} (\text{V})$	TYP.	UNIT
Input Capacitance	C_{IN}	—	1.8, 2.5, 3.3	6	pF
Bus I/O Capacitance	$C_{I/O}$	—	1.8, 2.5, 3.3	7	pF
Power Dissipation Capacitance	C_{PD}	$f_{IN} = 10 \text{ MHz}$ (Note 13)	1.8, 2.5, 3.3	20	pF

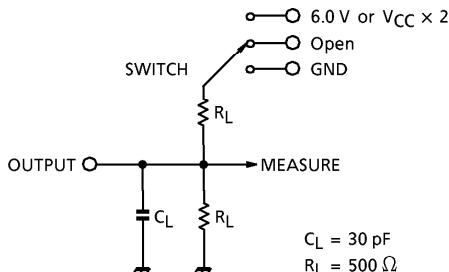
(Note 13) : C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

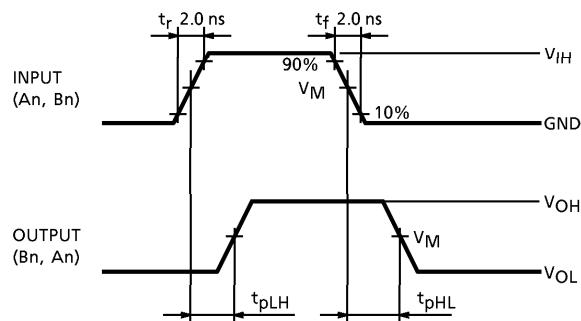
$$I_{CC(\text{opr.})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 18 \text{ (per bit)}$$

TEST CIRCUIT

Fig.1



PARAMETER	SWITCH
t_{pLH}, t_{pHL}	Open
t_{pLZ}, t_{pZL}	6.0 V @ $V_{CC} = 3.3 \pm 0.3 \text{ V}$ $V_{CC} \times 2$ @ $V_{CC} = 2.5 \pm 0.2 \text{ V}$ @ $V_{CC} = 1.8 \text{ V}$
t_{pHZ}, t_{pZH}	GND

AC WAVEFORMFig.2 t_{pLH}, t_{pHL} 

SYMBOL	V_{CC}		
	$3.3 \pm 0.3 \text{ V}$	$2.5 \pm 0.2 \text{ V}$	1.8 V
V_{IH}	2.7 V	V_{CC}	V_{CC}
V_M	1.5 V	$V_{CC}/2$	$V_{CC}/2$
V_X	$V_{OL} + 0.3 \text{ V}$	$V_{OL} + 0.15 \text{ V}$	$V_{OL} + 0.15 \text{ V}$
V_Y	$V_{OH} - 0.3 \text{ V}$	$V_{OH} - 0.15 \text{ V}$	$V_{OH} - 0.15 \text{ V}$

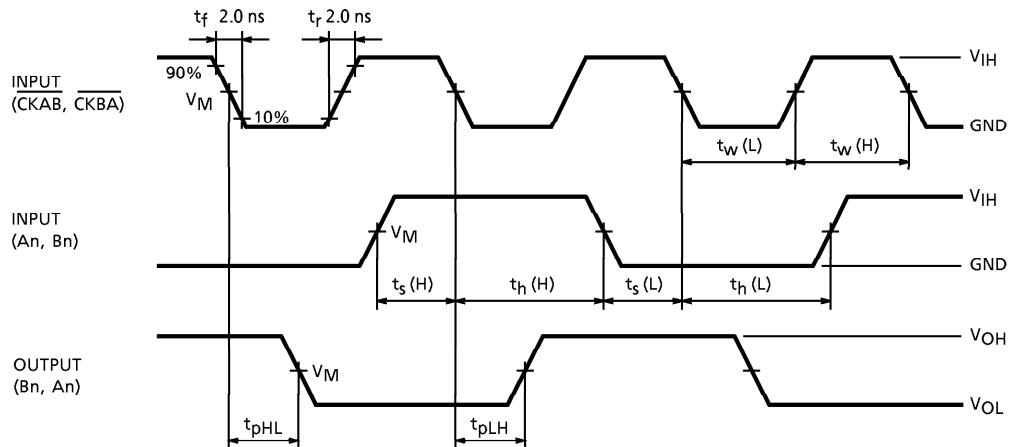
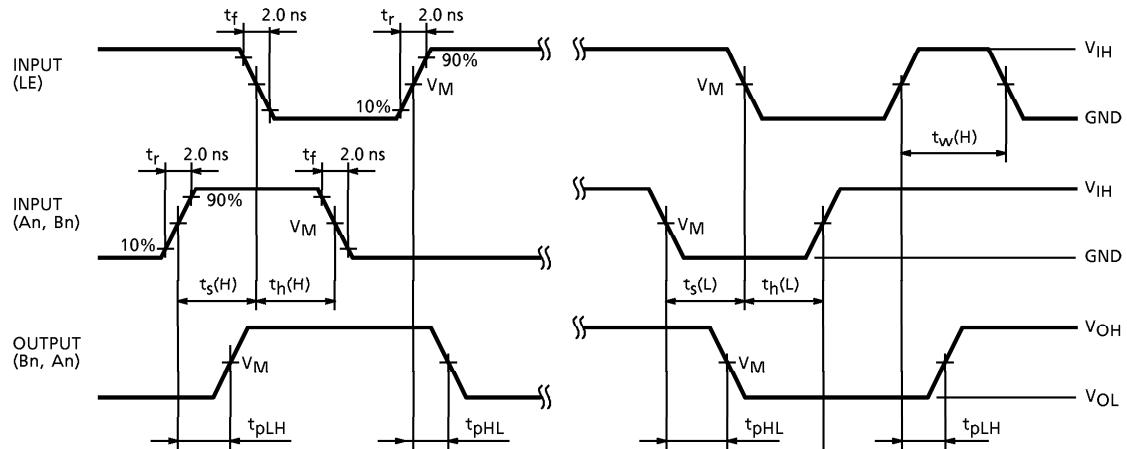
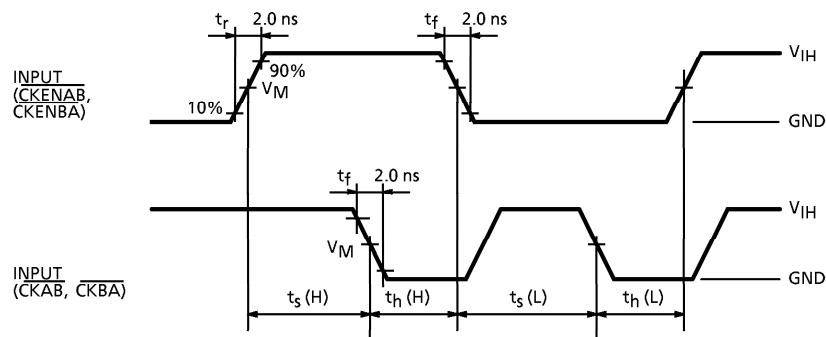
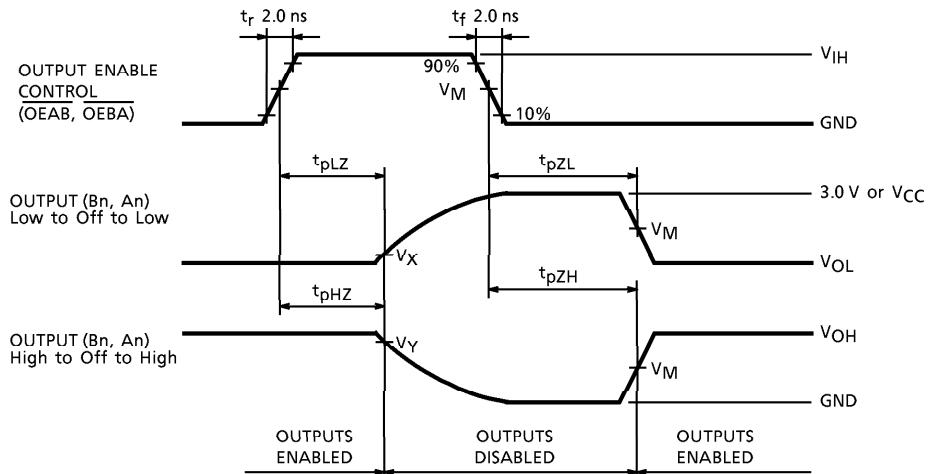
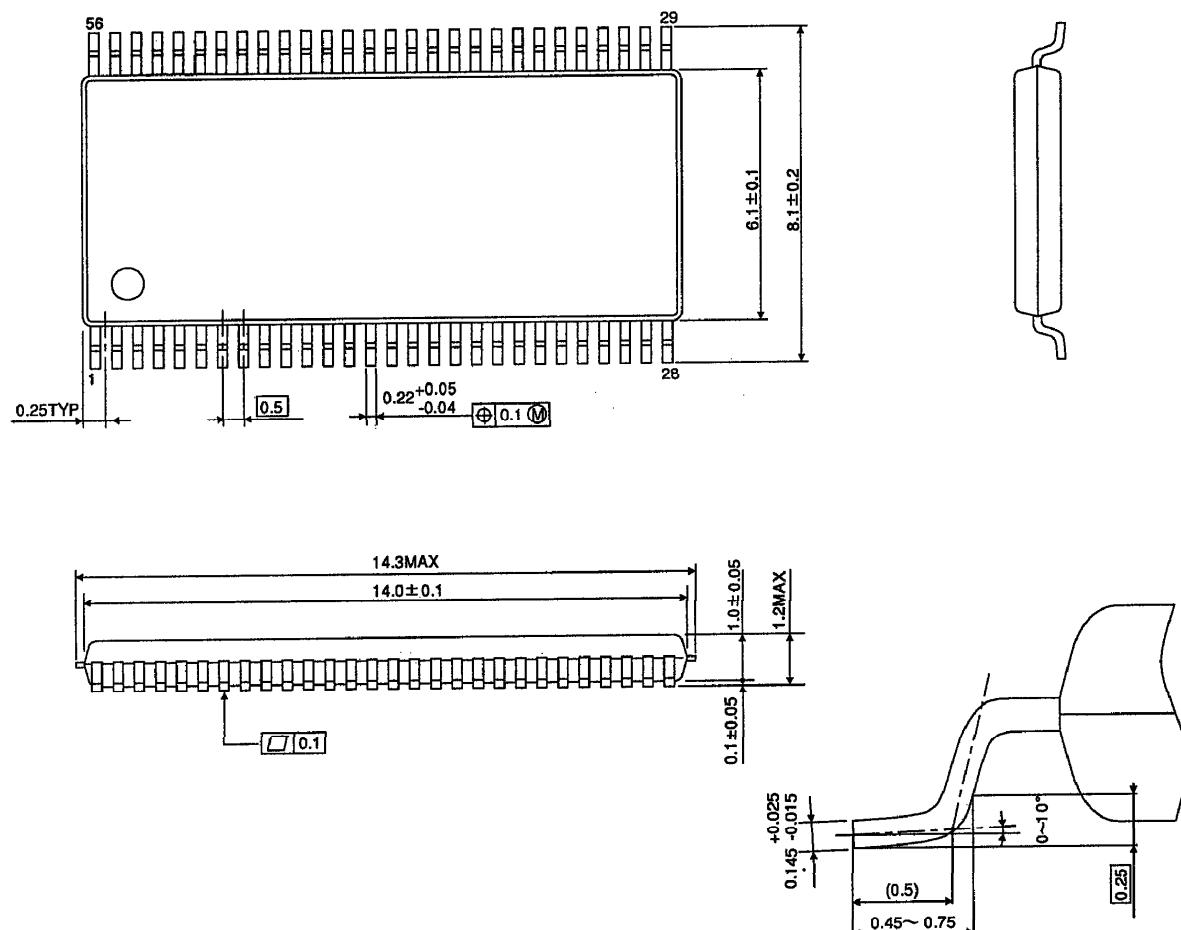
Fig.3 $t_{pLH}, t_{pHL}, t_w, t_s, t_h$ 

Fig.4 t_{pLH} , t_{pHL} , t_w , t_s , t_h Fig.5 t_s , t_h Fig.6 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH} 

PACKAGE DIMENSIONS

TSSOP56-P-0061-0.50

Unit : mm



Weight : 0.25 g (Typ.)

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000707EBA

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